

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/717,381	MAHISHI ET AL.	
Examiner	Art Unit	
Yong D. Pak	1652	

SEARCHED				
Class	Subclass	Date	Examiner	
435	189	10/24/2005	ΥP	
435	194	10/24/2005	YP	
435	195	10/24/2005	YP	
435	252.3	10/24/2005	YP	
435	320.1	10/24/2005	YP	
435	69.1	10/24/2005	YP	
435	71.1	10/24/2005	YP	
435	146	10/24/2005	YP	
435	252.33	10/24/2005	YP	
536	23.2	10/24/2005	YP	
536	23.7	10/24/2005	YP	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
435	146	10/24/2005	YP	
435	252.3	10/24/2005	YPYP	
435	23.7	10/24/2005	YP	
stic: seq id no:1		10/24/2005	YP	

SEARCH N (INCLUDING SEARC)
	DATE	EXMR
stic: seq id no:1	10/24/2005	YP
stn/east: see search history	10/24/2005	YP
inventor search	10/24/2005	